

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

First Named  
Inventor : David W. Duquette

Appln. No. : 09/767,199 ✓

Filed : January 22, 2001

For : IMPROVED LASER ALIGN SENSOR  
WITH SEQUENCING LIGHT  
SOURCES

Docket No.: C34.12-0021

Group Art Unit: 2877

Examiner:

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**INFORMATION DISCLOSURE STATEMENT**

Commissioner for Patents  
Washington, D.C. 20231

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134  
  
PATENT ATTORNEY

Sir:

The patents or publications listed on the enclosed PTO  
Form-1449 are submitted pursuant to 37 C.F.R. § 1.97. Copies of  
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The Director is authorized to charge any fee deficiency  
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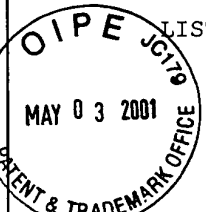
Respectfully submitted,

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FORM PTO-1449		Atty. Docket No.: C34.12-0021	Appl. No.: 09/767,199
 <p>LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT</p>		First Named Inventor:	
		David W. Duquette	
		Filing Date	Group Art:
		January 22, 2001	2877

## U.S. PATENT DOCUMENTS

Examiner Initial	Document No.	Date	Name	Class	Sub Class	Filing Date If Appropriate
AA	4,615,093	10/07/86	Tews et al.	29	407	
AB	5,278,634	01/11/94	Skunes et al.	356	400	
AC	5,559,727	02/24/96	Deley et al.	364	559	
AD	5,871,391	02/16/99	Pryor	451	9	
AE	5,900,940	05/04/99	Aoshima	356	375	
AF	08/904,950	08/01/97	Bartunek et al.			Pending
AG						

## FOREIGN PATENT DOCUMENTS

	Document No.	Date	Country	Class	Sub Class	Translation Yes No
AH	WO 99/62313	12/02/99	WIPO			(Abstract Only)
AI	JP 9-210626	08/12/97	Japan			(Abstract Only)
AJ	JP 9-246794	09/19/97	Japan			(Abstract Only)
AK	JP 9-307298	11/28/97	Japan			X
AL	JP 10-93298	04/10/98	Japan			(Abstract Only)
AM	JP 10-148514	06/02/98	Japan			(Abstract Only)
AN	JP 10-284890	10/23/98	Japan			(Abstract Only)
AO	JP 11-251797	09/17/99	Japan			(Abstract Only)
AP	JP 2000-31697	02/28/00	Japan			(Abstract Only)
AQ	JP 2000-13400	05/12/00	Japan			(Abstract Only)

## OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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